Search Notes	S

Application/Control No.	Applicant(s)/Patent under Reexamination
10/632,499	OLSCHEWSKI, FRANK
Examiner	Art Unit
Dennis Rosario	2624

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH		· · · · · · · · · · · · · · · · · · ·
	DATE	EXMR
Fast, all dB	1/4/07	DR
IEEE-trajectory (near) pixel and filter#-	115102	DR
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